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HUF76629D3S

Data Sheet

October 2013

N-Channel Logic Level UltraFET Power MOSFET 100 V, 20 A, 54 m Ω

Packaging



Features

- Ultra Low On-Resistance
 - r_{DS(ON)} = 0.052Ω, V_{GS} = 10V
 - $r_{DS(ON)} = 0.054\Omega, V_{GS} = 5V$
- Simulation Models
 - Temperature Compensated PSPICE® and SABER™ Electriecal Models
 - Spice and SABER Thermal Impedance Models
 - www.fairchildsemi.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Switching Time vs R_{GS} Curves

Ordering Information

PART NUMBER	PACKAGE	BRAND
HUF76629D3ST	TO-252AA	76629D

Absolute Maximum Ratings T_C = 25°C, Unless Otherwise Specified

	HUF76629D3ST	UNITS
Drain to Source Voltage (Note 1) V _{DSS}	100	V
Drain to Gate Voltage (R _{GS} = 20kΩ) (Note 1)	100	V
Gate to Source Voltage V _{GS}	±16	V
Drain Current		
Continuous (T _C = 25° C, V _{GS} = 5V) I _D	20	А
Continuous ($T_c = 25^{\circ}C$, $V_{GS} = 10V$) (Figure 2) I_D	20	A
Continuous (T _C = 100 ^o C, V _{GS} = 5V) \ldots I _D	20	А
Continuous (T _C = 100 ^o C, V _{GS} = 4.5V) (Figure 2) \dots I _D	20	А
Pulsed Drain Current	Figure 4	
Pulsed Avalanche RatingUIS	Figures 6, 17, 18	
Power Dissipation P _D	110	W
Derate Above 25°C	0.74	W/ ^o C
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10sTL	300	°C
Package Body for 10s, See Techbrief TB334 T _{pkg}	260	°C
NOTES:		

1. $T_J = 25^{\circ}C$ to $150^{\circ}C$.

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

Product reliability information can be found at http://www.fairchildsemi.com/products/discrete/reliability/index.html For severe environments, see our Automotive HUFA series.

All Fairchild semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

PARAMETER	SYMBOL	TEST C	ONDITIONS	MIN	TYP	MAX	UNITS
OFF STATE SPECIFICATIONS	ļ	+			ļ		
Drain to Source Breakdown Voltage BV		$I_{D} = 250 \mu A, V_{GS} = 0V$ (Figure 12)	100	-	-	V
		$I_{D} = 250 \mu A, V_{GS} = 0V$,	$T_{C} = -40^{\circ}C$ (Figure 12)	90	-	-	V
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 95V, V _{GS} = 0V		-	-	1	μA
		$V_{DS} = 90V, V_{GS} = 0V, T_{CS} = 0V, T_$	T _C = 150 ⁰ C	-	-	250	μA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 16V$		-	-	±100	nA
ON STATE SPECIFICATIONS							
Gate to Source Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 250 \mu A$	(Figure 11)	1	-	3	V
Drain to Source On Resistance	rDS(ON)	I _D = 20A, V _{GS} = 10V (F	igures 9, 10)	-	0.0415	0.052	Ω
	. ,	I _D = 20A, V _{GS} = 5V (Figure 9)		-	0.046	0.054	Ω
		I _D = 20A, V _{GS} = 4.5V (I	Figure 9)	-	0.047	0.055	Ω
THERMAL SPECIFICATIONS					-	ļ	
Thermal Resistance Junction to Case	R _{θJC}	TO-252AA		-	-	1.36	°C/W
Thermal Resistance Junction to Ambient	R _{θJA}	_		-	-	100	°C/W
SWITCHING SPECIFICATIONS (V_{GS} = $\ensuremath{V_{GS}}$	= 4.5V)						
Turn-On Time	^t ON	$V_{DD} = 50V, I_D = 20A$		-	-	190	ns
Turn-On Delay Time	^t d(ON)	[→] V _{GS} = 4.5V, R _{GS} = 6.89 → (Figures 15, 21, 22)	Ω	-	11	-	ns
Rise Time	t _r		_ (Figures 15, 21, 22)	-	114	-	ns
Turn-Off Delay Time	td(OFF)		-	38	-	ns	
Fall Time	t _f		-	60	-	ns	
Turn-Off Time	tOFF			-	-	145	ns
SWITCHING SPECIFICATIONS (V_{GS} = $\ensuremath{SWITCHING}$	= 10V)					1	
Turn-On Time	t _{ON}	$V_{DD} = 50V, I_D = 20A$		-	-	50	ns
Turn-On Delay Time	^t d(ON)	V _{GS} = 10V,R _{GS} = 8.2Ω (Figures 16, 21, 22)		-	6.8	-	ns
Rise Time	t _r			-	28	-	ns
Turn-Off Delay Time	^t d(OFF)			-	67	-	ns
Fall Time	t _f	_		-	60	-	ns
Turn-Off Time	^t OFF	_		-	-	190	ns
GATE CHARGE SPECIFICATIONS	I						1
Total Gate Charge	Q _{g(TOT)}	$V_{GS} = 0V \text{ to } 10V$	V _{DD} = 50V,	-	38	46	nC
Gate Charge at 5V	Q _{g(5)}	$V_{00} = 0V to 5V$	I _D = 20A,	-	21	25	nC
Threshold Gate Charge	Q _{g(TH)}		$I_{\alpha}(REE) = 1.0mA$	-	1.2	1.6	nC
Gate to Source Gate Charge	Q _{gs}			-	3.3	-	nC
Gate to Drain "Miller" Charge	Q _{gd}			-	10	-	nC
CAPACITANCE SPECIFICATIONS	0.				-		<u> </u>
Input Capacitance	C _{ISS}	$V_{DS} = 25V, V_{GS} = 0V,$		- 1	1285		pF
Output Capacitance	C _{OSS}	f = 1MHz		-	270		pF
Reverse Transfer Capacitance	C _{RSS}	(Figure 13)		-	65	-	pF

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	V _{SD}	I _{SD} = 20A	-	-	1.25	V
		I _{SD} = 10A	-	-	1.00	V
Reverse Recovery Time	t _{rr}	$I_{SD} = 20A, dI_{SD}/dt = 100A/\mu s$	-	-	110	ns
Reverse Recovered Charge	Q _{RR}	I _{SD} = 20A, dI _{SD} /dt = 100A/μs	-	-	370	nC

Typical Performance Curves



10⁻²

t, PULSE WIDTH (s)

10⁻¹

10⁻⁴

10⁻³

10⁻⁵

10¹

10⁰





FIGURE 5. FORWARD BIAS SAFE OPERATING AREA











NOTE: Refer to Fairchild Application Notes AN9321 and AN9322. FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING

CAPABILITY



FIGURE 8. SATURATION CHARACTERISTICS



FIGURE 10. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

Typical Performance Curves (Continued)







FIGURE 13. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



FIGURE 15. SWITCHING TIME vs GATE RESISTANCE



FIGURE 12. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260. FIGURE 14. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT



FIGURE 16. SWITCHING TIME vs GATE RESISTANCE

Test Circuits and Waveforms



FIGURE 17. UNCLAMPED ENERGY TEST CIRCUIT



FIGURE 19. GATE CHARGE TEST CIRCUIT



FIGURE 21. SWITCHING TIME TEST CIRCUIT



FIGURE 18. UNCLAMPED ENERGY WAVEFORMS



FIGURE 20. GATE CHARGE WAVEFORMS



FIGURE 22. SWITCHING TIME WAVEFORM

PSPICE Electrical Model

.SUBCKT HUF76629D3 2 1 3 ; rev 30 July 1999

CA 12 8 2.32e-9 CB 15 14 2.32e-9 CIN 6 8 1.22e-9



.ENDS

NOTE: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model



SPICE Thermal Model

REV 26 July 1999

HUF76629D3

CTHERM1 th 6 2.45e-3 CTHERM2 6 5 8.15e-3 CTHERM3 5 4 7.40e-3 CTHERM4 4 3 7.45e-3 CTHERM5 3 2 1.01e-2 CTHERM6 2 tl 7.49e-2

RTHERM1 th 6 9.00e-3 RTHERM2 6 5 1.80e-2 RTHERM3 5 4 9.15e-2 RTHERM4 4 3 2.43e-1 RTHERM5 3 2 3.50e-1 RTHERM6 2 tl 3.62e-1

SABER Thermal Model

SABER thermal model HUF76629D3

template thermal_model th tl thermal_c th, tl

ctherm.ctherm1 th 6 = 2.45e-3ctherm.ctherm2 6 5 = 8.15e-3ctherm.ctherm3 5 4 = 7.40e-3ctherm.ctherm4 4 3 = 7.45e-3ctherm.ctherm5 3 2 = 1.01e-2ctherm.ctherm6 2 tl = 7.49e-2

rtherm.rtherm1 th 6 = 9.00e-3 rtherm.rtherm2 6 5 = 1.80e-2 rtherm.rtherm3 5 4 = 9.15e-2 rtherm.rtherm4 4 3 = 2.43e-1 rtherm.rtherm5 3 2 = 3.50e-1 rtherm.rtherm6 2 tl = 3.62e-1 }





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